

ComScire QNG Model R2000KU Validation Tests of Randomness (Representative Test Results)

NIST Statistical Test Suite for the Validation of Random Number Generators

The National Institute of Standards and Technology (NIST) provides a statistical testing suite, specified in Special Publication 800-22rev1a, consisting of 15 tests that were developed to test the randomness of binary sequences generated by a TRNG or PRNG. The NIST Statistical Test Suite (NIST STS) software and documentation can be downloaded from their [Cryptographic Toolkit web page](#). In order to run the NIST STS, some modifications to the source code were necessary for the software to compile using Visual Studio 2008 running in a Windows Vista environment. These modifications consist of implementing the error (*erf*) and complementary error (*erfc*) functions that do not exist in the Microsoft's math library.

The Cephes C language special functions math library, already included in the NIST STS software, was used to implement the error and complementary error functions. All *erf* and *erfc* functions in the source code were replaced by *cephes_erf* and *cephes_erfc* functions, respectively. After the successful compilation of the source code, a number of tests were completed to confirm the functionality of the software. The test suite contains sample data files of 1,000,000 bits in length to be analyzed. These include the binary expansions of constants e , π , $\sqrt{2}$ and $\sqrt{3}$. For each sample file, the NIST STS battery of tests were performed and compared to the empirical results found in the SP800-22rev1a documentation Appendix B.

Following the confirmation that the test suite is operating properly, two binary files of 80,000,000 and 1,000,000 bits in length were generated using our QNG Model R2000KU (SN: QWR20141) to be analyzed. The generation of the 1Mb data file was necessary to run the Random Excursions, Random Excursions Variant, and Spectral DFT tests. These tests were unable to generate results when using the 80Mb data file. The warning messages for the Random Excursions and Random Excursions Variant tests were "Test not applicable. There are an insufficient number of cycles". The warning message for the Spectral test was "Unable to allocate working arrays for the DFT". Therefore, all tests except for Random Excursions, Random Excursions Variant, and Spectral DFT were applied for the 80Mb data file.

All test results are recorded in the following Table 1. The Block Frequency, Non-overlapping Template Matching, Overlapping Template Matching, Approximate Entropy, Linear Complexity and Serial tests require user prescribed input parameters. The exact values used in these examples have been included in parenthesis beside the name of the statistical test. In the case of the Non-overlapping Templates test, a Kolmogorov-Smirnov test (KS-test) was performed for the collection of 148 *P-values*. In the case of the Random Excursions and Random Excursions Variant tests, only one of the possible 8 and 18 *P-values*, respectively, has been reported.

NIST Battery of Tests Results	
Statistical Test	P-value
Frequency	0.504760
Block Frequency (m = 128)	0.011722
Cumulative Sums-Forward	0.156774
Cumulative Sums-Reverse	0.546617
Runs	0.759893
Long Runs of Ones	0.933389
Rank	0.790140
Spectral DFT	0.123153
Non-overlapping Templates (m = 9)	0.903437
Overlapping Templates (m = 9)	0.072533
Universal	0.377014
Approximate Entropy (m = 10)	0.672195
Random Excursions (x = +1)	0.297413
Random Excursions Variant (x = -1)	0.090169
Linear Complexity (M = 500)	0.693184
Serial (m = 16, $\nabla \Psi_m^2$)	0.232591
Serial (m = 16, $\nabla^2 \Psi_m^2$)	0.413173

Table 1— NIST Test Suite Results for R2000KU.

DIEHARD: A Battery of Tests of Randomness

The DIEHARD Battery of Tests of Randomness, developed by Prof. George Marsaglia, contains a collection of 15 tests to examine the randomness of binary sequences generated by a TRNG or PRNG. The complete testing suite, including documentation and software, can be found directly from the [DIEHARD website](#). Windows executable files are provided for simple use of the testing suite. The DIEHARD tests require a large binary file of random integers, at least 80 million bits, to be tested. Therefore, the same 80Mb data file used for the NIST STS battery of tests was used for the DIEHARD test.

For the 80Mb data file all of the statistical tests were applied and the resulting *P-values* recorded in the following Table 2. In the case of the Birthday Spacings, Binary Rank (6x8 matrices), OPSO, OQSO, DNA, Count-the-1's (specified bytes), This is a Parking Lot, The Minimum Distance, 3DSpheres, Overlapping Sums, and Runs (up & down) tests, only the K-S tests has been reported.

DIEHARD Battery of Tests Results	
Statistical Test	P-value
Birthday Spacings	0.853236
Overlapping 5-Permutation	0.826763
Binary Rank (31x31)	0.931721
Binary Rank (32x32)	0.961805
Binary Rank (6x8)	0.298009
Bitstream	0.831529
OPSO	0.595235
OQSO	0.292152
DNA	0.191343
Count-the-1's (byte stream)	0.564874
Count-the-1's (specified bytes)	0.414715
This is a Parking Lot	0.014159
The Minimum Distance	0.381348
3DSpheres	0.751597
Squeeze	0.670939
Overlapping Sums	0.146658
Runs (up)	0.918427
Runs (down)	0.251912
Craps (no. of wins)	0.493110
Craps (throws/game)	0.798057

Table 2— DIEHARD Test Suite Results for R2000KU.